Application/Control No.	Applicant(s)/Patent under Reexamination		
10/549,297	TAKEHARA ET AL.		
Examiner	Art Unit	•	
Nguyen N. Hanh	2834		

SEARCHED				
SEARCHED				
Class	Subclass	Date	Examiner	
310	90	12/21/2006	HN	
310	90.5	12/21/2006	HN	
310	156.01	12/21/2006	HN	
update seunds	all	1/25/07	HN	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
3/0	90	7/25/07	HN		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
PG Pub Text search so interference search Print out	7/25/07	HN		
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